

# P1-09 Fabrication method of SPAD sensor for automotive LiDAR to compensate the process fluctuation by feedforward system

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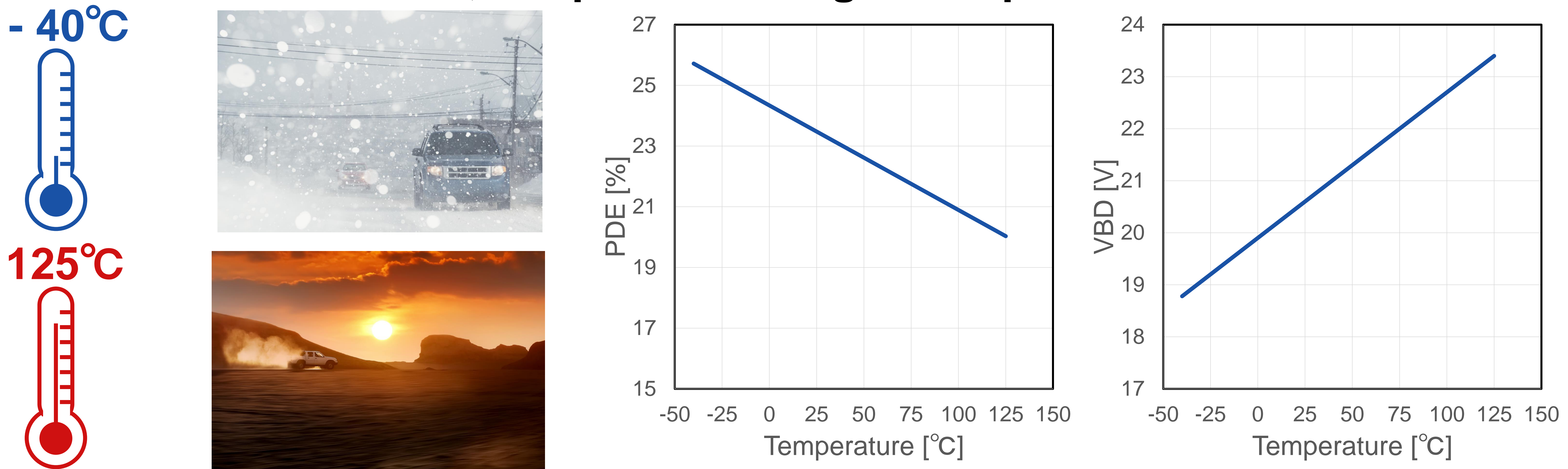
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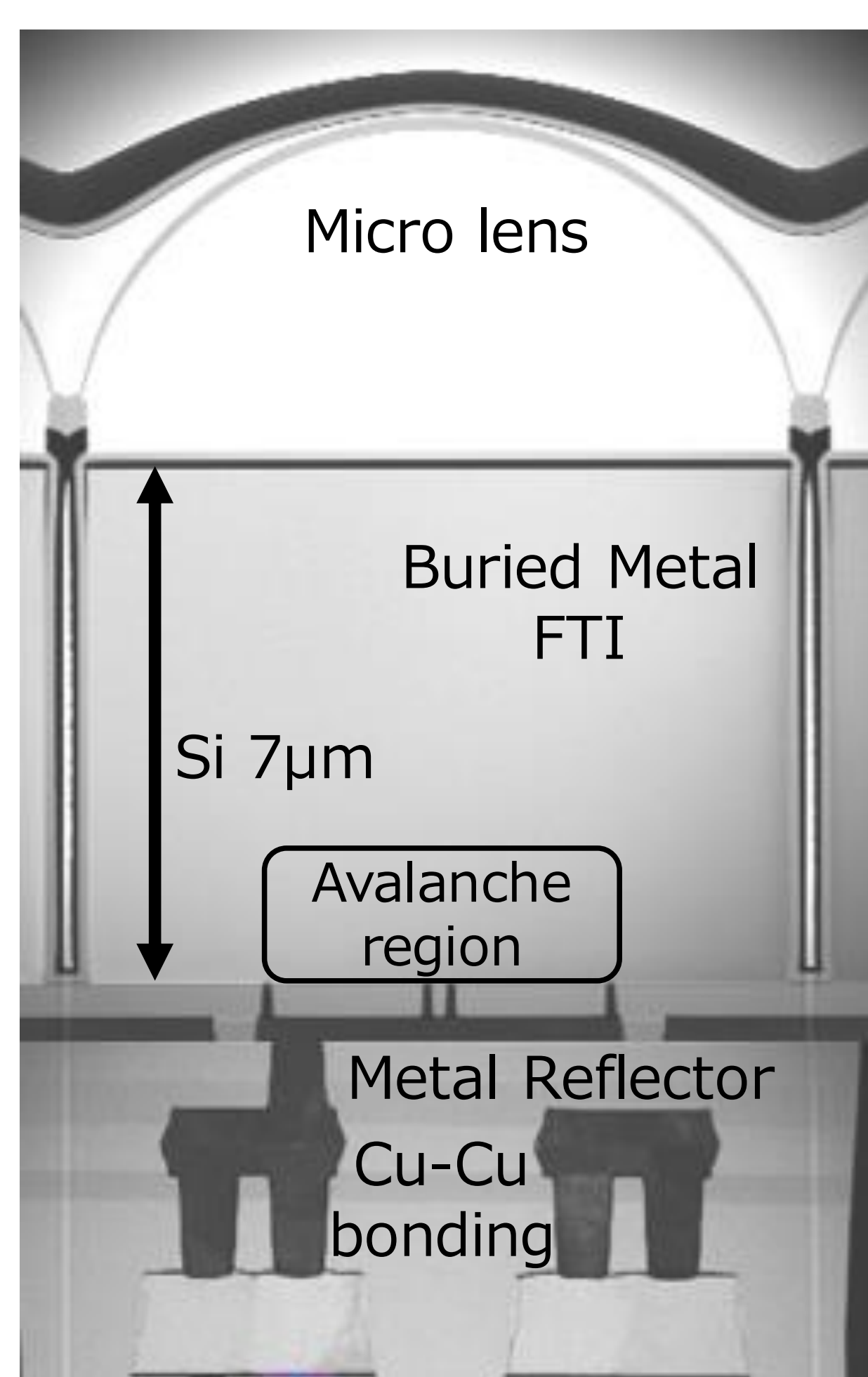
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## Requirement from Automotive Electronics Council(AEC)

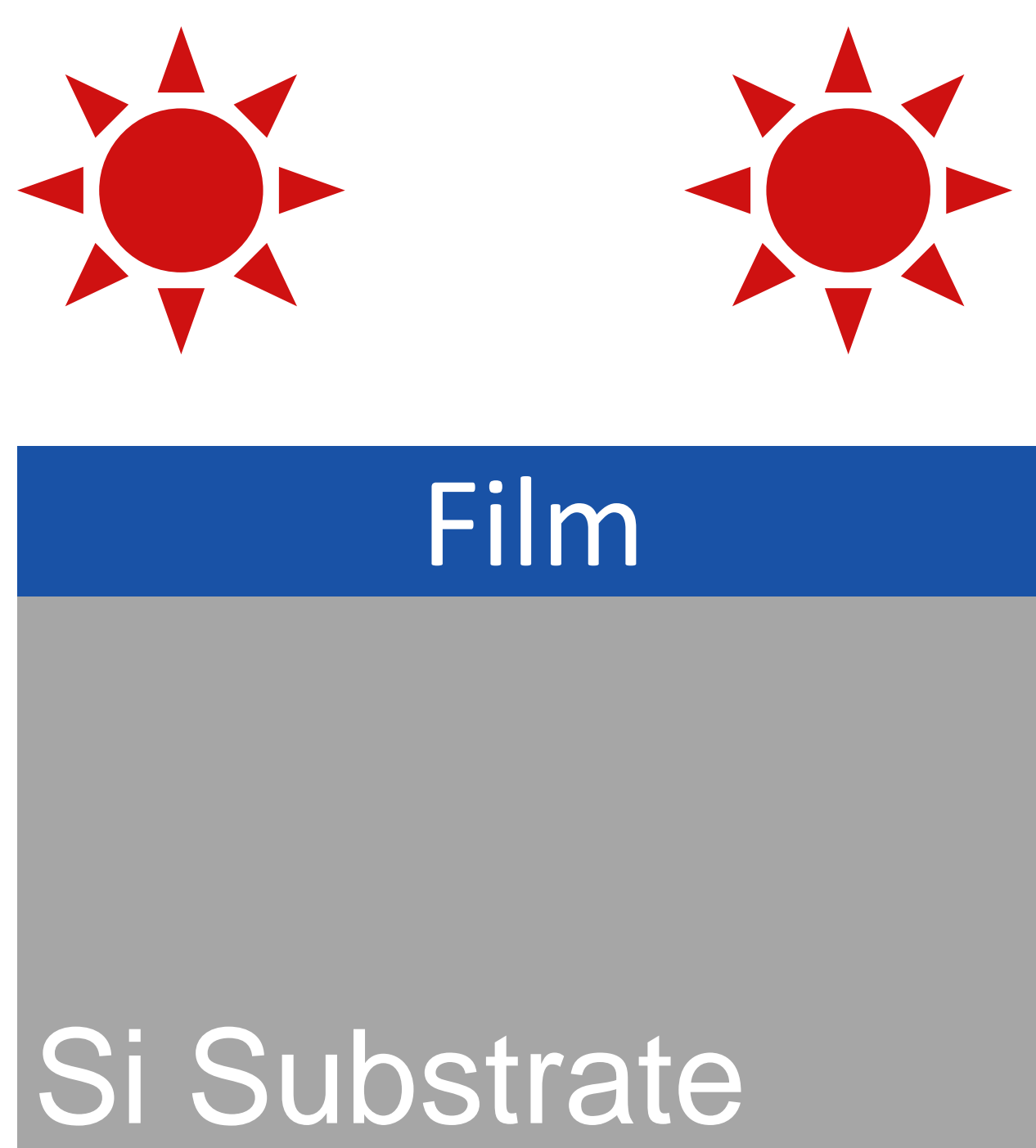
For the automotive, temperature range is required from  $-40^{\circ}\text{C}$  to  $125^{\circ}\text{C}$



## SPAD Structure and Process Fluctuation

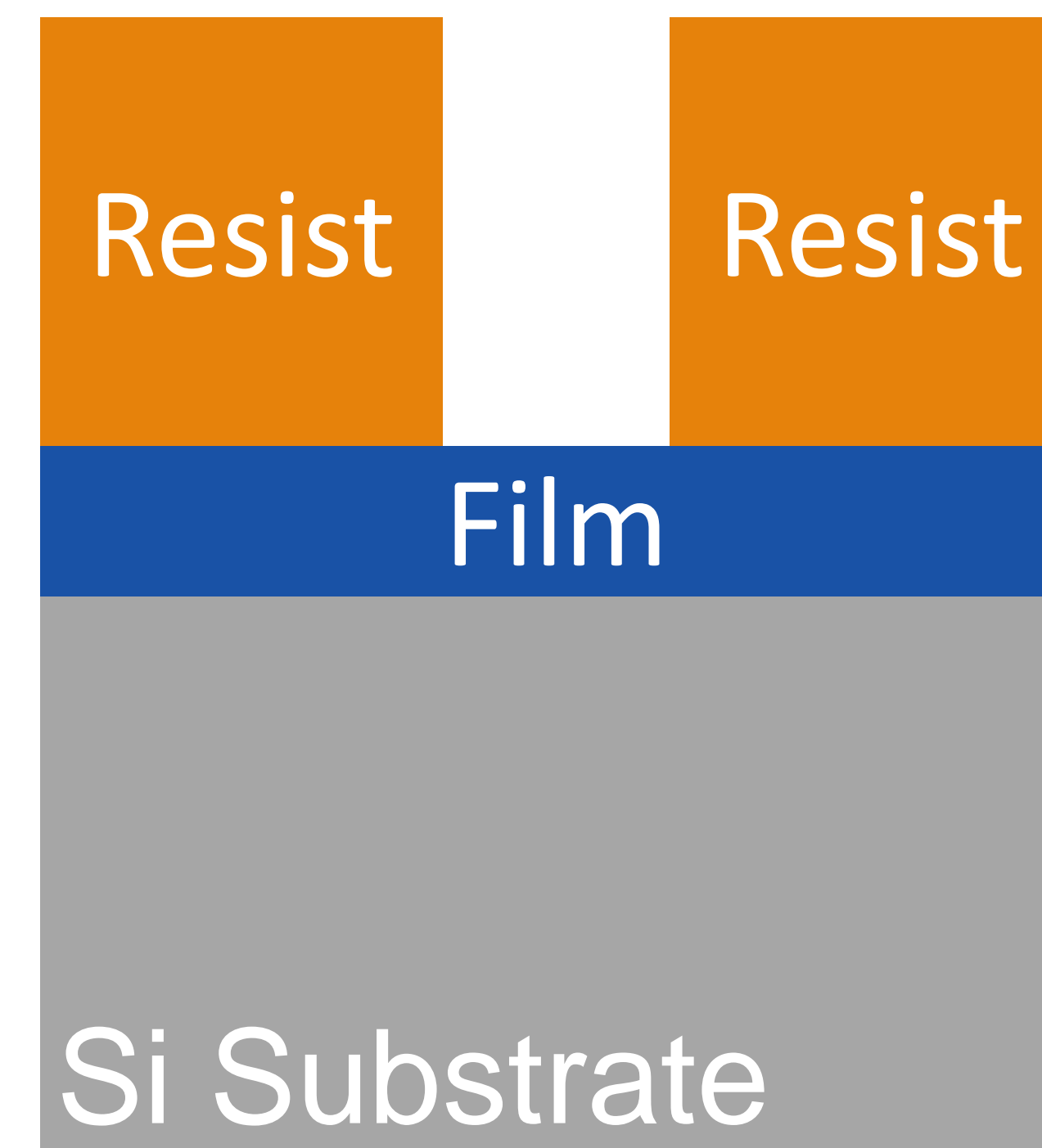


Anneal/Deposit



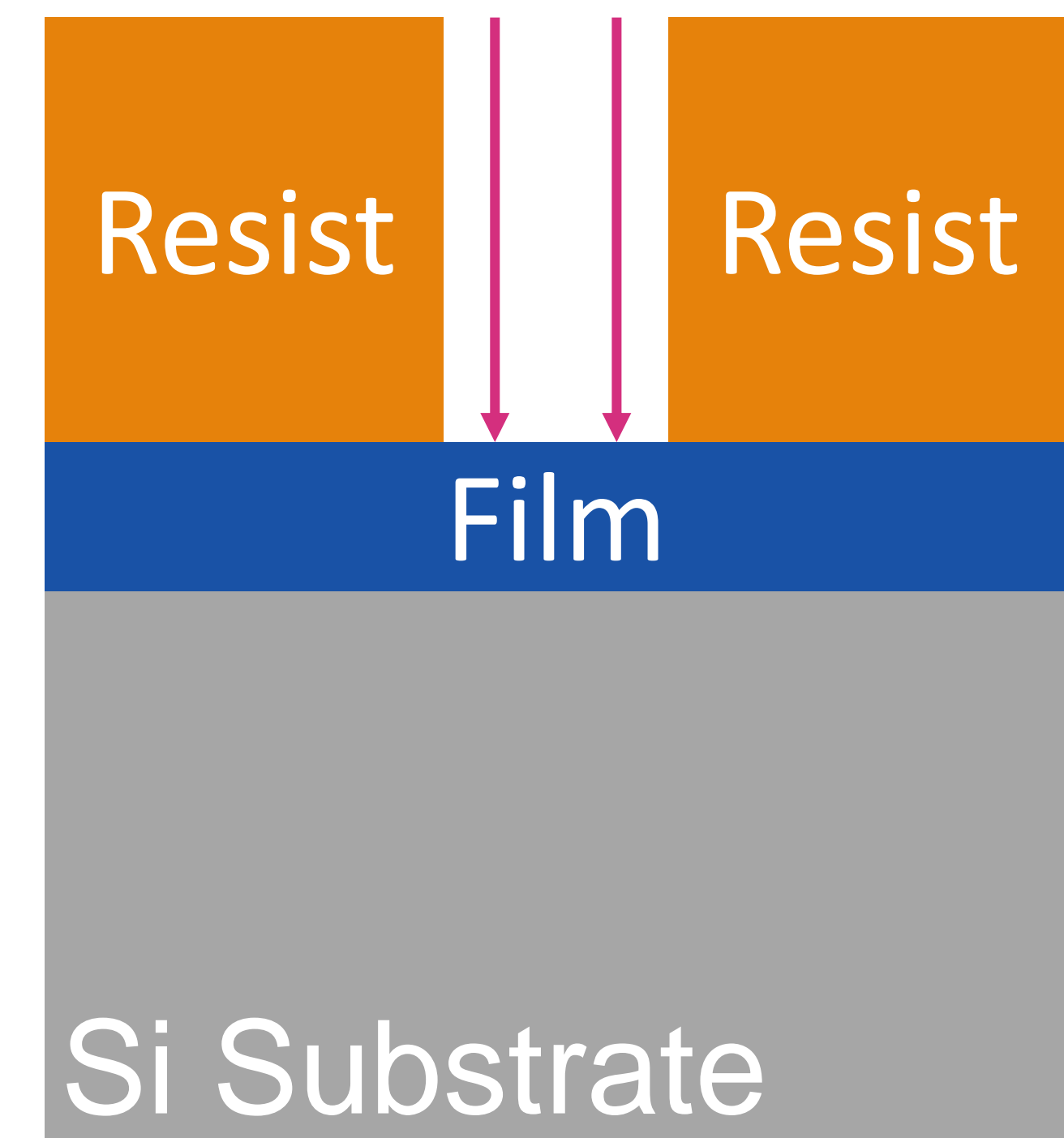
Anneal Temperature  
Film Thickness

Photo Lithography



Aperture Width  
Resist Taper

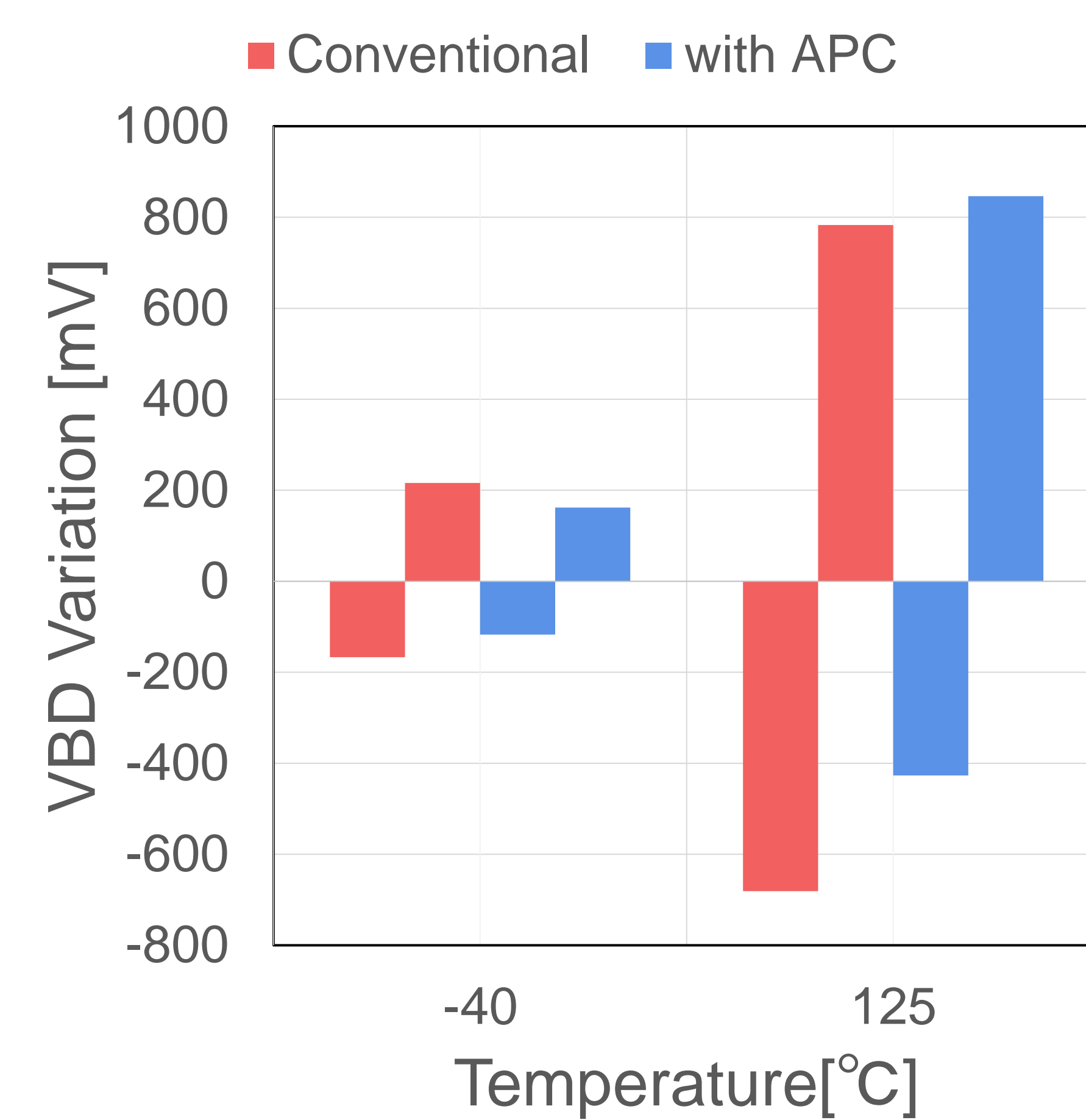
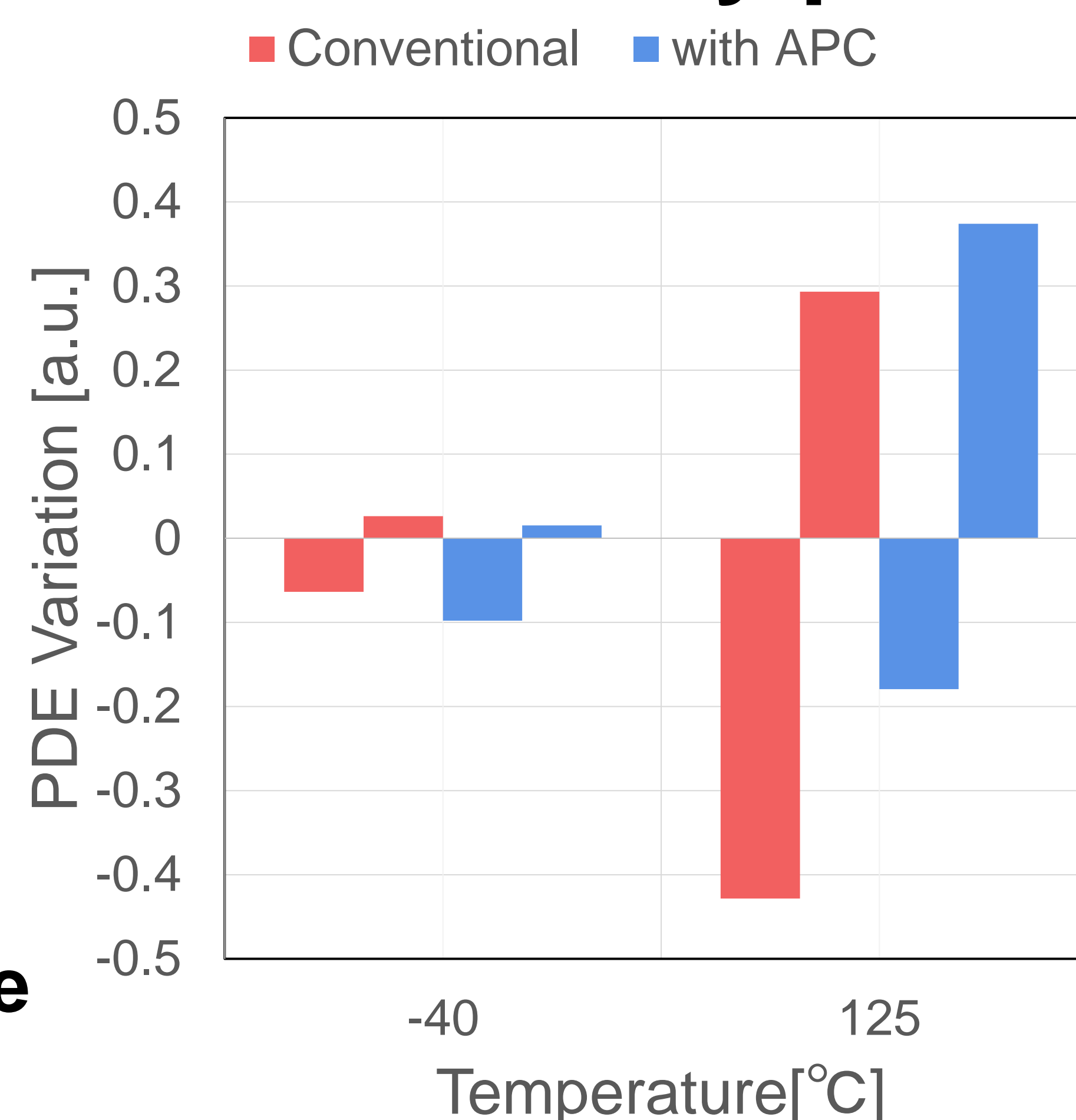
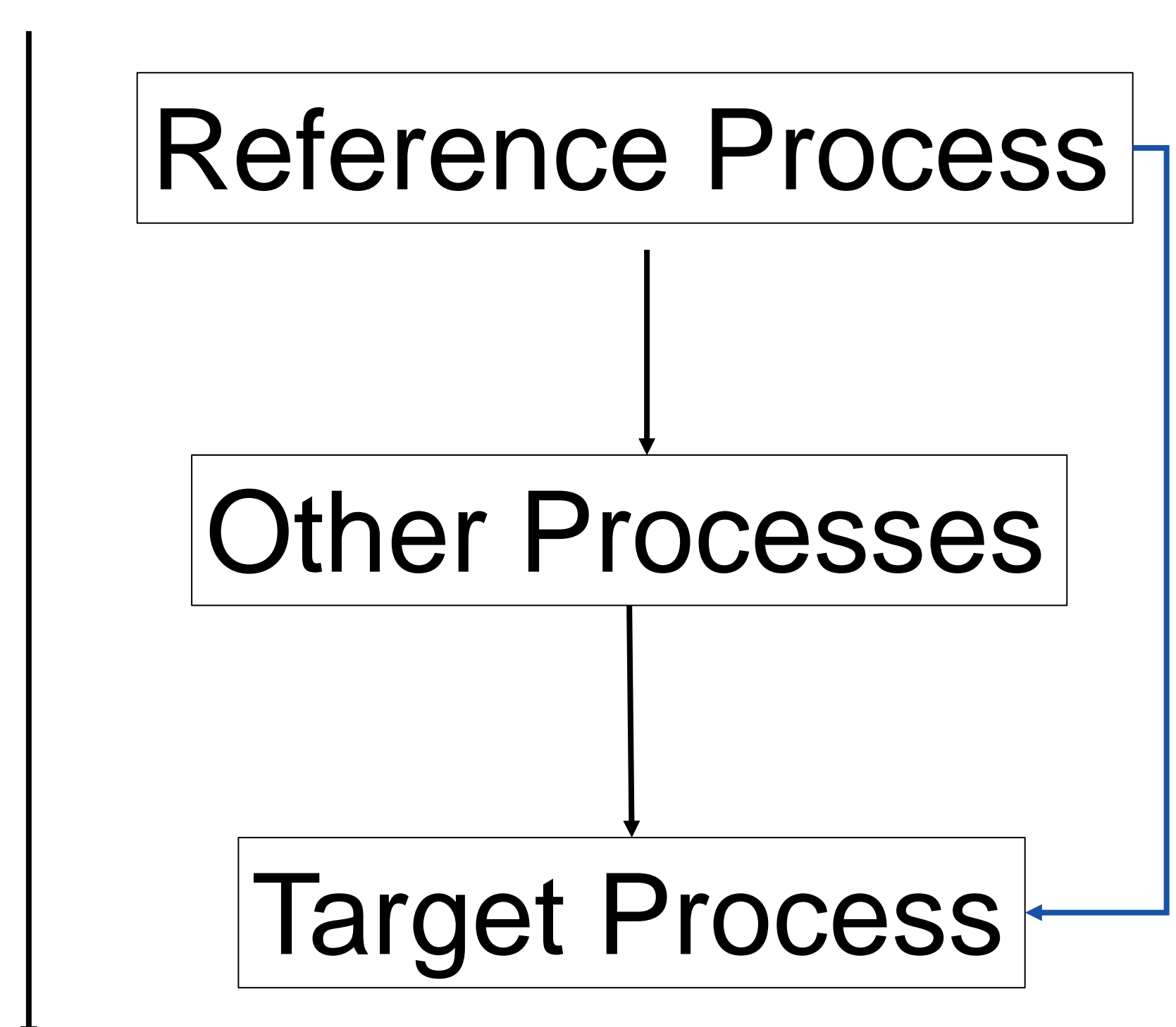
Ion Implant



Peak Concentration  
Tail Profile

## Process Feedforward System

Reduce the PDE and VBD variation by process feedforward system



Monitor the Ref. Process Performance  
Tune the Target Process Condition